

FCP16N60 / FCPF16N60 N-Channel SuperFET[®] MOSFET 600 V, 16 A, 260 mΩ

Features

- 650V @ T_{.I} = 150°C
- Typ. R_{DS(on)} = 220 mΩ
- Ultra Low Gate Charge (Typ. Q_g = 55 nC)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 110 pF)
- 100% Avalanche Tested

Applications

- Solar Inverter
- AC-DC Power Supply

August 2014

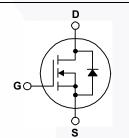
FCP16N60 / FCPF16N60 — N-Channel SuperFET[®] MOSFET

Description

SuperFET[®] MOSFET is Fairchild Semiconductor's first generation of high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low onresistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET MOSFET is very suitable for the switching power applications such as PFC, server/telecom power, FPD TV power, ATX power and industrial power applications.







Absolute Maximum Ratings

Symbol		Parameter		FCP16N60	FCPF16N60	Unit
V _{DSS}	Drain-Source Voltage			600		V
ID	Drain Current	- Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		16 10.1	16* 10.1*	A A
I _{DM}	Drain Current	- Pulsed	(Note 1)	48	48*	А
V _{GSS}	Gate-Source Voltage			± 30		V
E _{AS}	Single Pulsed Avalanche Energy			450		mJ
I _{AR}	Avalanche Curren	(Note 1)	16		А	
E _{AR}	Repetitive Avalanche Energy (Note		(Note 1)	20.8		mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	4.5		V/ns
P _D	Power Dissipation	(T _C = 25°C) - Derate Above 25°C		167 1.33	37.9 0.3	W W/°C
T _{J,} T _{STG}	Operating and Storage Temperature Range			-55 to +150		°C
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			300		°C

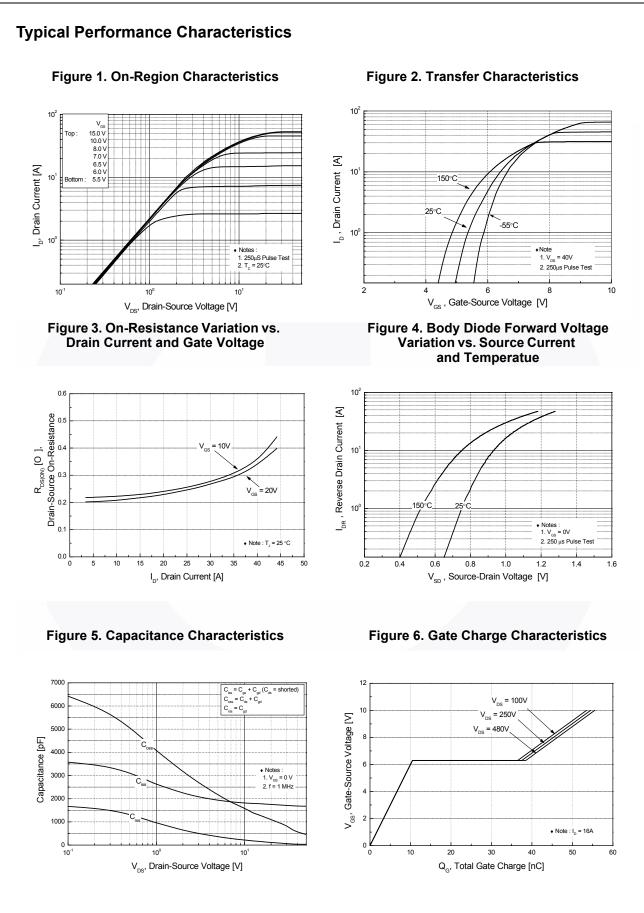
*Drain current limited by maximum junction temperature.

Thermal Characteristics

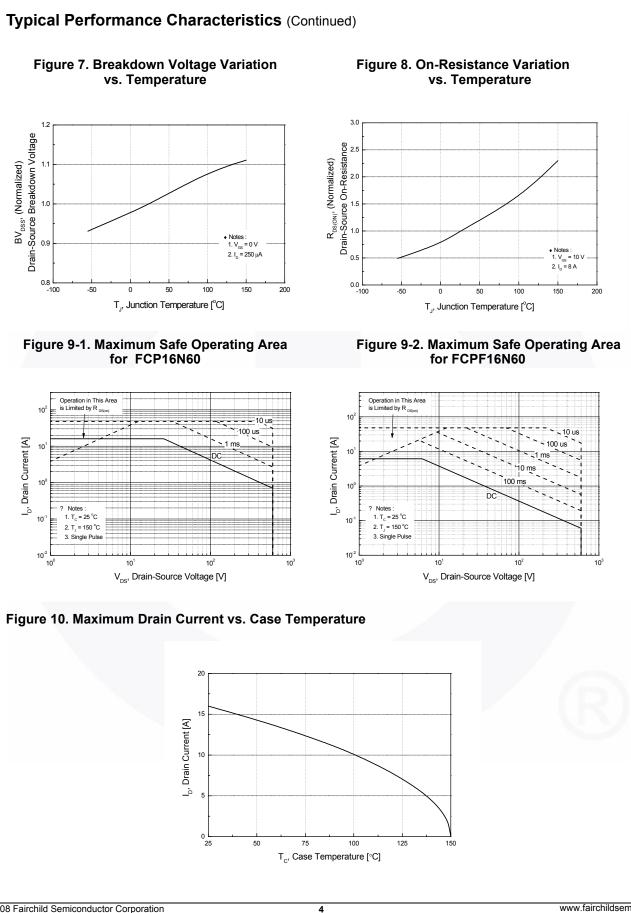
Symbol	Parameter	FCP16N60	FCPF16N60	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.75	3.3	°C/W
$R_{ extsf{ heta}JA}$	Thermal Resistance, Junction-to-Ambient	62.5	62.5	°C/W

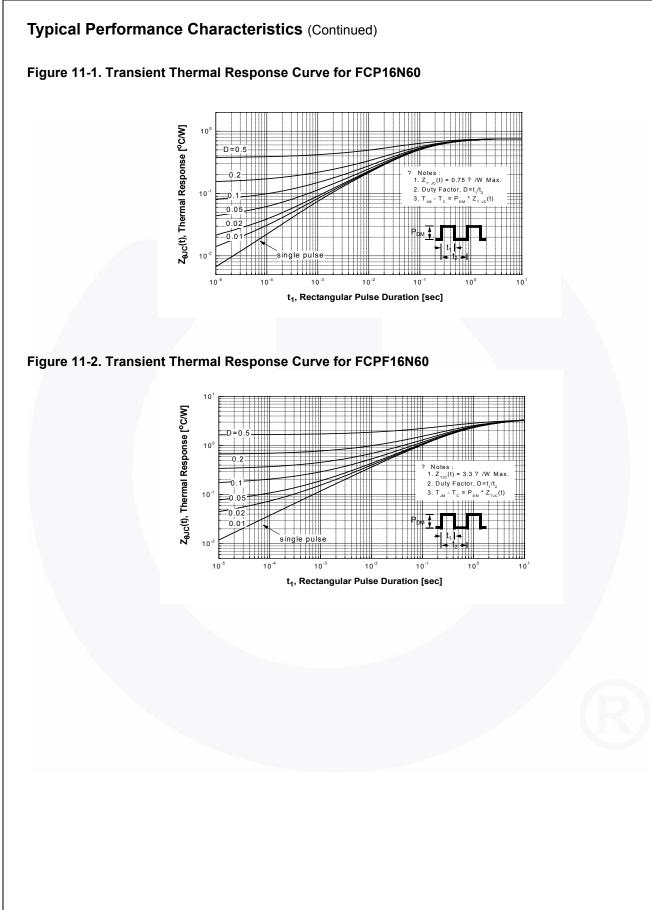
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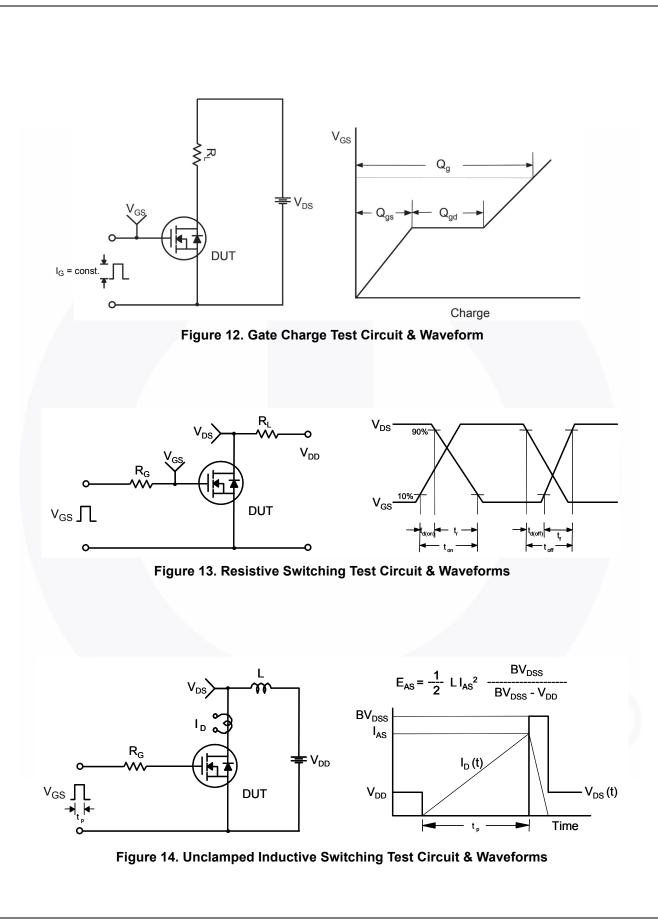
60		Package	Packing Method	Reel Size	Тар	e Width	Qua	ntity
	Part NumberTop MarkPateFCP16N60FCP16N60T		Tube	N/A		N/A	50 units	
FCPF16N60 FCPF16N60 TO			Tube	N/A		N/A	50 units	
Charac	cteristics T _C = 25	^o C unless	otherwise noted.					
	Parameter				Min.	Тур.	Max.	Unit
teristics							I	
			I _D = 250 μA. V _{CS} = 0 V.	T ₁ = 25 ^o C	600	-	_	V
Drain to Se			$I_D = 250 \ \mu\text{A}, \ V_{GS} = 0 \ V, \ T_J = 150^{\circ}\text{C}$		-	650	-	V
Breakdown Voltage Temperature Coefficient			$I_D = 250 \ \mu$ A, Referenced to 25° C		-	0.6	-	V/ºC
Drain-Source Avalanche Breakdown Voltage		wn	V _{GS} = 0 V, I _D = 16 A			700	-	v
			V _{DS} = 600 V, V _{GS} = 0 V		-	-	1	
					-	-	10	μA
Gate to Bo	ody Leakage Current		V _{GS} = ±30 V, V _{DS} = 0 V			-	±100	nA
teristics								
Gate Thre	shold Voltage		V _{GS} = V _{DS} , I _D = 250 μA		3.0	-	5.0	V
Static Drain to Source On Resistance				-	0.55	0.26	Ω	
Forward Transconductance						11.5	-	S
haracteri	stics			I. I.		1	1	
1	t Capacitance		$V_{\rm DS} = 25 \text{ V}, \text{ V}_{\rm GS} = 0 \text{ V},$		-	1730	2250	pF
Output Ca					-	960	1150	pF
	•		t = 1 MHz		-	85	-	pF
			V _{DS} = 480 V, V _{GS} = 0 V, f = 1 MHz		-	45	60	pF
					-	110	-	pF
				-	-	55	70	nC
	-			-	10.5	13	nC	
	-		(Note 4)			28	-	nC
Equivalent	ů		f = 1 MHz		-	1.7	-	Ω
Characte	ristics		1					1
1					-	42	85	ns
,			$V_{pp} = 300 V l_p = 16 A$		-			ns
				-	-			ns
			(Note 4)		-			ns
		urce Diode	Forward Current		-		16	А
					-	-	48	Α
					-	-	1.4	V
			$V_{GS} = 0 V, I_{SD} = 10 A$ $V_{GS} = 0 V, I_{SD} = 16 A,$ $dI_F/dt = 100 A/\mu s$		-	435	-	ns
	ecovery Charge				-	7.0	-	μC
	teristics Drain to Si Breakdown Coefficient Drain-Sou Voltage Zero Gate Gate to Bo teristics Gate Thre Static Drai Forward T haracteri Input Capa Output Ca Reverse T Output Ca Effective O Total Gate Gate to Sc Gate to Dr Equivalent Character Turn-On D Turn-On R Turn-Off D Turn-Off Fa Ce Diode Maximum I Drain to Sc	Parameter teristics Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Drain-Source Avalanche Breakdow Voltage Zero Gate Voltage Drain Current Gate to Body Leakage Current teristics Gate Threshold Voltage Static Drain to Source On Resista Forward Transconductance haracteristics Input Capacitance Output Capacitance Output Capacitance Output Capacitance Output Capacitance Total Gate Charge at 10V Gate to Drain "Miller" Charge Equivalent Series Resistance Characteristics Turn-On Delay Time Turn-Off Delay Time Turn-Off Fall Time Ce Diode Characteristics Maximum Continuous Drain to Source	Parameter teristics Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Drain-Source Avalanche Breakdown Voltage Zero Gate Voltage Drain Current Gate to Body Leakage Current teristics Gate Threshold Voltage Static Drain to Source On Resistance Forward Transconductance haracteristics Input Capacitance Output Capacitance Output Capacitance Output Capacitance Effective Output Capacitance Output Capacitance Gate to Source Gate Charge Gate to Drain "Miller" Charge Equivalent Series Resistance Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Fall Time Ce Diode Characteristics Maximum Continuous Drain to Source Diode Maximum Pulsed Drain to Source Diode For Drain to Source Diode Forward Voltage	teristicsDrain to Source Breakdown Voltage $I_D = 250 \ \mu$ A, $V_{GS} = 0 \ V$, $I_D = 250 \ \mu$ A, $V_{GS} = 0 \ V$, $I_D = 250 \ \mu$ A, $V_{GS} = 0 \ V$, $I_D = 250 \ \mu$ A, ReferenceDrain-Source Avalanche Breakdown Voltage $V_{GS} = 0 \ V$, $I_D = 16 \ A$ Zero Gate Voltage Drain Current $V_{DS} = 600 \ V$, $V_{GS} = 0 \ V$, $V_{DS} = 480 \ V$, $T_C = 1250$ (Gate to Body Leakage CurrentGate Threshold Voltage $V_{GS} = \pm 30 \ V$, $V_{DS} = 0 \ V$ Static Drain to Source On Resistance $V_{GS} = 10 \ V$, $I_D = 8 \ A$ Forward Transconductance $V_{DS} = 40 \ V$, $I_D = 8 \ A$ haracteristicsInput CapacitanceOutput Capacitance $V_{DS} = 480 \ V$, $V_{GS} = 0 \ V$, $f = 1 \ MHz$ Output Capacitance $V_{DS} = 480 \ V$, $V_{GS} = 0 \ V$ Gate to Source Gate Charge $V_{DS} = 480 \ V$, $V_{GS} = 0 \ V$ Gate to Source Gate Charge $V_{DS} = 10 \ V$ Gate to Drain "Miller" Charge $F = 1 \ MHz$ Characteristics $Turn-On \ Rise \ Time$ Turn-On Delay Time $V_{CS} = 10 \ V$ Turn-Off Delay Time $V_{CS} = 10 \ V, \ R_G = 25 \ \Omega$ Turn-Off Fall Time $V_{DD} = 300 \ V, \ I_D = 16 \ A$ Maximum Continuous Drain to Source Diode Forward CurrentMaximum Continuous Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward CurrentDrain to Source Diode Forward CurrentDrain to Source Diode Forward Current	ParameterTest ConditionsteristicsIn the Source Breakdown VoltageDrain to Source Breakdown Voltage Temperature CoefficientID = 250 μ A, VGS = 0 V, TJ = 150°CBreakdown Voltage Temperature CoefficientID = 250 μ A, Referenced to 25°CDrain-Source Avalanche Breakdown VoltageVGS = 0 V, ID = 16 AVageVDS = 600 V, VGS = 0 VZero Gate Voltage Drain CurrentVDS = 480 V, TC = 125°CGate to Body Leakage CurrentVGS = ±30 V, VDS = 0 VteristicsGate Threshold VoltageVGS = 10 V, ID = 8 AForward TransconductanceVDS = 40 V, ID = 8 AharacteristicsInput CapacitanceVDS = 25 V, VGS = 0 V, f = 1 MHzQutput CapacitanceVDS = 25 V, VGS = 0 V, f = 1 MHzOutput CapacitanceVDS = 480 V, VGS = 0 V, f = 1 MHzCharacteristicsVDS = 0 V to 400 V, VGS = 0 V, f = 1 MHzCharacteristicsVDS = 480 V, ID = 16 A, VGS = 10 V, Gate to Drain "Miller" ChargeTurn-On Delay Time Turn-On Rise TimeVDD = 300 V, ID = 16 A, VGS = 10 V, GS = 10 V, RG = 25 \Omega, (Note 4)CharacteristicsVDD = 300 V, ID = 16 A, VGS = 10 V, RG = 25 \Omega, (Note 4)Colode CharacteristicsVDD = 300 V, ID = 16 A, VGS = 10 V, RG = 25 \Omega, (Note 4)Turn-On Bley Time Turn-Off Fall Time(Note 4)Cobiode CharacteristicsVGS = 0 V, VGS = 0 V, VGS = 10 V, VGS = 10 V, RG = 25 \Omega, (Note 4)Turn-Off Collay Time Turn-Off Fall Time(Note Forward Current Maximum Pulsed Drain to Source Diode Forwa	ParameterTest ConditionsMin.teristicsDrain to Source Breakdown Voltage $I_D = 250 \ \mu A, V_{GS} = 0 \ V, T_J = 25^{\circ}C$ 600Breakdown Voltage Temperature Coefficient $I_D = 250 \ \mu A, V_{GS} = 0 \ V, T_J = 150^{\circ}C$ -Drain-Source Avalanche Breakdown Voltage $V_{GS} = 0 \ V, I_D = 16 \ A$ -Zero Gate Voltage Drain Current $V_{DS} = 600 \ V, V_{GS} = 0 \ V$ -Gate to Body Leakage Current $V_{GS} = 480 \ V, T_C = 125^{\circ}C$ -Gate Threshold Voltage $V_{GS} = 10 \ V, I_D = 8 \ A$ -Forward Transconductance $V_{DS} = 40 \ V, I_D = 8 \ A$ -Proved Transconductance $V_{DS} = 25 \ V, V_{GS} = 0 \ V, I_D = 8 \ A$ -Provard Transconductance $V_{DS} = 25 \ V, V_{GS} = 0 \ V, I_D = 8 \ A$ -ParateristicsInput Capacitance Output Capacitance $V_{DS} = 40 \ V, I_D = 8 \ A$ -Output Capacitance Output Capacitance $V_{DS} = 0 \ V, 0_{GS} = 0 \ V, I = 1 \ MHz$ -Effective Output Capacitance Gate to Drain "Miller" Charge $V_{DS} = 10 \ V, 0_{SS} = 0 \ V, I = 1 \ MHz$ -CharacteristicsTurn-On Delay Time Turn-On Bleay TimeV_{DD} = 300 \ V, I_D = 16 \ A, 0 \ V_{GS} = 10 \ V, 0_{GS} = 10 \	$\begin{tabular}{ c c c c c } \hline Parameter Test Conditions Min. 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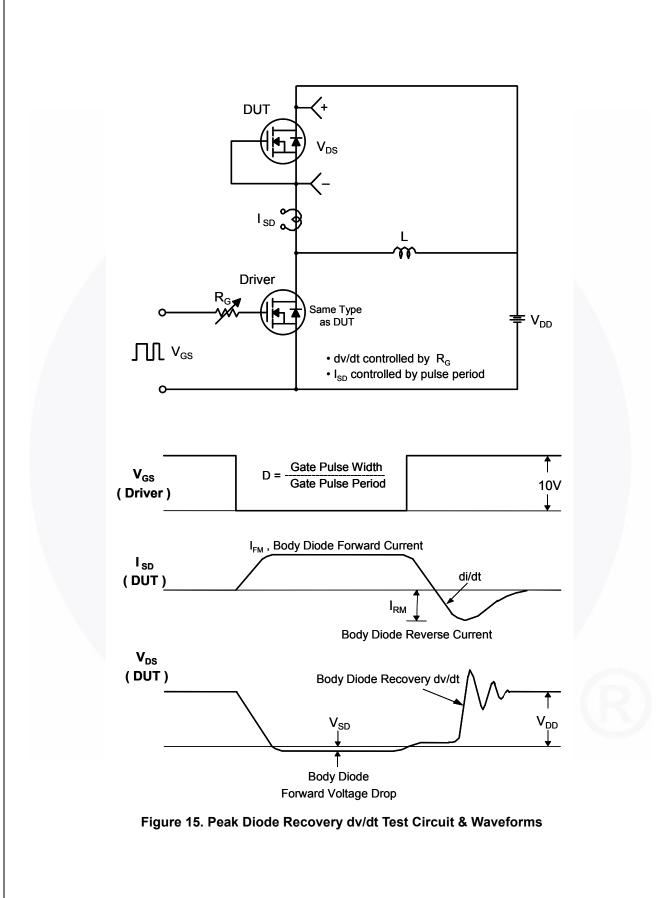


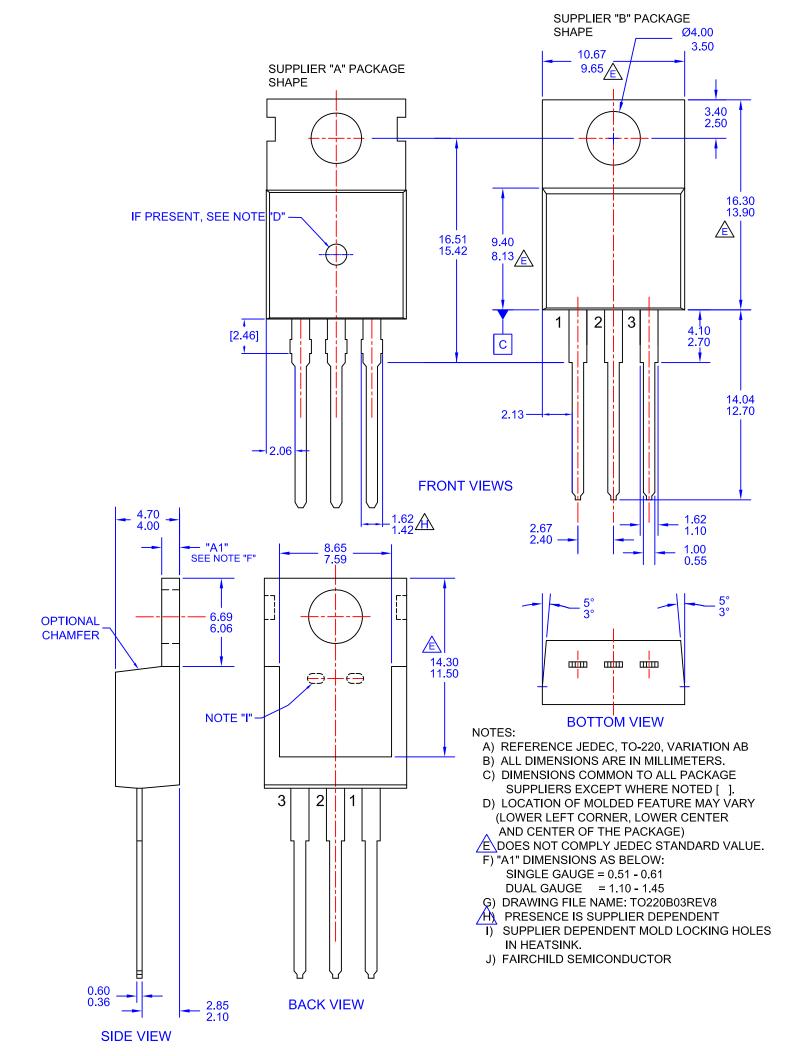


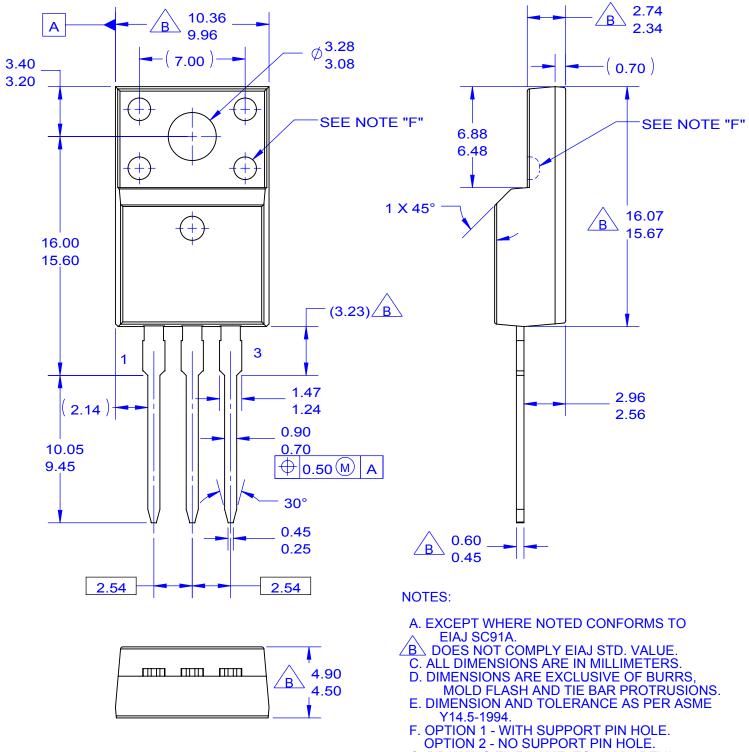


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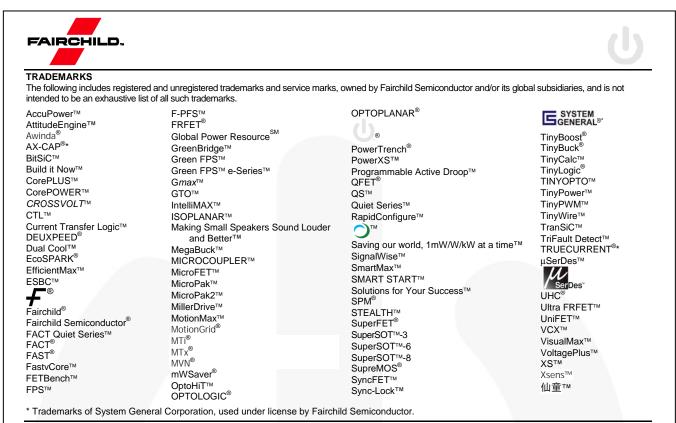
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Preliminary First Production		Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.			
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